

BENCHTOP SCANNING ELECTRON MICROSCOPE



Descriptions

The instrument scanning image using improved electron optic, higher magnification, and built-in image processing to further enhance image quality and resolution at lower accelerating voltage. It is used for observing particle samples, polymers, metals, biological samples and heavy metal coating.

Further Information

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Brand-Model

PHENOM PRO X

Basic Specifications

Light optical magnification : 27 to 160x

Electron optical magnification range: 160-350,000x

Detector:

Backscattered electron detector

(standard), Energy-dispersive X-ray detector

(standard), Secondary electron detector

(optional)

Sample size: Up to 25 mm diameter

(optional 32 mm)

Sample height: Up to 35 mm (optional 100 mm)

Equipment Website (Manufacturer)

<https://www.thermofisher.com>

Types of samples

Dry powder

Location

Central Analytical Laboratory
(T02, 01-28-10)

Operator

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